

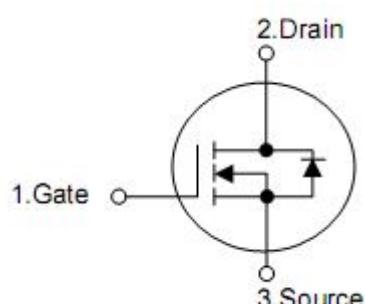
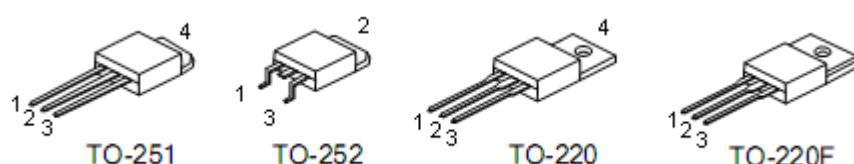
## 1. Description

The KIA4N60H N-Channel enhancement mode silicon gate power MOSFET is designed for high voltage, high speed power switching applications such as switching regulators, switching converters, solenoid, motor drivers, relay drivers.

## 2. Features

- $R_{DS(ON)} = 2.3\Omega @ V_{GS} = 10V$
- Low gate charge (typical 13.5nC)
- High ruggedness
- Fast switching capability
- Avalanche energy specified
- Improved dv/dt capability

## 3. Pin configuration



Pin	Function
1	Gate
2	Drain
3	Source
4	Drain

## 4. Absolute maximum ratings

Parameter		Symbol	Rating				Units
			TO220	TO220F	TO251	TO252	
Drain-source voltage		V <sub>DSS</sub>	600				V
Gate-source voltage		V <sub>GSS</sub>	±30				V
Drain current continuous	T <sub>C</sub> =25°C	I <sub>D</sub>	4.0	4.0*	2.8		A
	T <sub>C</sub> =100°C		2.4	2.4*	1.8		A
Drain current pulsed (note1)		I <sub>DM</sub>	16	16*	12		A
Avalanche energy	Repetitive (note1)	E <sub>AR</sub>	9.3		5.5		mJ
	Single pulse (note2)	E <sub>AS</sub>	180				mJ
Peak diode recovery dv/dt (note3)		dv/dt	4.5				V/ns
Total power dissipation	T <sub>C</sub> =25°C	P <sub>D</sub>	93	31	55		W
	Derate above 25°C		0.74	0.24	0.44		W/°C
Junction temperature		T <sub>J</sub>	+150				°C
Storage temperature		T <sub>STG</sub>	-55~+150				°C

\*Drain current limited by maximum junction temperature.

## 5. Thermal characteristics

Parameter	Symbol	Rating				Unit
		TO220	TO220F	TO251	TO252	
Thermal resistance, junction-ambient	R <sub>thJA</sub>	62.5		110		°C/W
Thermal resistance, case-to-sink typ	R <sub>thJS</sub>	0.5	--	50		
Thermal resistance junction-case	R <sub>thJC</sub>	1.35	4.05	2.25		

## 6. Electrical characteristics

( $T_J=25^\circ\text{C}$ ,unless otherwise notes)

Parameter	Symbol	Conditions	Min	Typ	Max	Unit
<b>Off characteristics</b>						
Drain-source breakdown voltage	$\text{BV}_{\text{DSS}}$	$V_{\text{GS}}=0\text{V}, I_D=250\mu\text{A}$	600	-	-	V
Zero gate voltage drain current	$I_{\text{DSS}}$	$V_{\text{DS}}=600\text{V}, V_{\text{GS}}=0\text{V}$	-	-	1	$\mu\text{A}$
		$V_{\text{DS}}=480\text{V}, T_C=125^\circ\text{C}$	-	-	10	$\mu\text{A}$
Gate-body leakage current	$I_{\text{GSS}}$	$V_{\text{GS}}=30\text{V}, V_{\text{DS}}=0\text{V}$	-	-	100	nA
		$V_{\text{GS}}=-30\text{V}, V_{\text{DS}}=0\text{V}$	-	-	-100	nA
Breakdown voltage temperature coefficient	$\Delta \text{BV}_{\text{DSS}}/\Delta T_J$	$I_D=250\mu\text{A}$	-	0.6	-	$\text{V}/^\circ\text{C}$
<b>On characteristics</b>						
Gate threshold voltage	$V_{\text{GS(TH)}}$	$V_{\text{DS}}=V_{\text{GS}}, I_D=250\mu\text{A}$	2.0	-	4.0	V
Static drain-source on-resistance	$R_{\text{DS(ON)}}$	$V_{\text{DS}}=10\text{V},$ $I_D=2.0\text{A}(\text{TO220, TO220F})$ $I_D=1.4\text{A}(\text{TO251, TO252})$	-	2.3	2.7	$\Omega$
<b>Dynamic characteristics</b>						
Input capacitance	$C_{\text{ISS}}$	$V_{\text{DS}}=25\text{V}, V_{\text{GS}}=0\text{V},$ $f=1\text{MHz}$	-	500	-	pF
Output capacitance	$C_{\text{OSS}}$		-	45	-	pF
Reverse transfer capacitance	$C_{\text{RSS}}$		-	4.5	-	pF
<b>Switching characteristics</b>						
Turn-on delay time	$t_{\text{D(ON)}}$	$V_{\text{DD}}=300\text{V},$ $I_D=4.0\text{A}(\text{TO220, TO220F})$ $I_D=2.8\text{A}(\text{TO251, TO252})$ $R_G=25\Omega$ (note4,5)	-	10	-	ns
Rise time	$t_R$		-	32	-	ns
Turn-off delay time	$t_{\text{D(OFF)}}$		-	32	-	ns
Fall time	$t_F$		-	40	-	ns
Total gate charge	$Q_G$	$V_{\text{DS}}=480\text{V},$ $I_D=4.0\text{A}(\text{TO220, TO220F})$ $I_D=2.8\text{A}(\text{TO251, TO252})$ $V_{\text{GS}}=10\text{V}$ (note4,5)	-	13.5	-	nC
Gate-source charge	$Q_{\text{GS}}$		-	2.2	-	nC
Gate-drain charge	$Q_{\text{GD}}$		-	5.4	-	nC
<b>Drain-source diode characteristics</b>						
Drain-source diode forward voltage	$V_{\text{SD}}$	$V_{\text{GS}}=0\text{V},$ $I_{\text{SD}}=4.0\text{A}(\text{TO220, TO220F})$ $I_{\text{SD}}=2.8\text{A}(\text{TO251, TO252})$	-	-	1.4	V
Continuous drain-source current	$I_{\text{SD}}$	TO220,TO220F	-	-	4.0	A
		TO251,TO252	-	-	2.8	
Pulsed drain-source current	$I_{\text{SM}}$	TO220,TO220F	-	-	16.0	A
		TO251,TO252	-	-	12	
Reverse recovery time	$t_{\text{RR}}$	$I_{\text{SD}}=4.0\text{A}(\text{TO220, TO220F})$ $I_{\text{SD}}=2.8\text{A}(\text{TO251, TO252})$ $dI_{\text{SD}}/dt=100\text{A}/\mu\text{s}$ (note 4)	-	250	-	ns
Reverse recovery charge	$Q_{\text{RR}}$		-	1.8	-	$\mu\text{C}$

Notes: 1. Repetitive rating : pulse width limited by maximum junction temperature

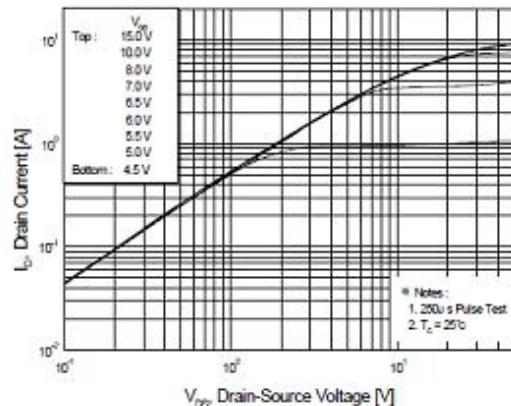
2.  $L=20\text{mH}$ ,  $I_{\text{AS}}=4.0\text{A}$ ,  $V_{\text{DD}}=50\text{V}$ ,  $R_G=25\Omega$ , starting  $T_J=25^\circ\text{C}$

3.  $I_{\text{SD}} \leq 4.0\text{A}, dI/dt \leq 200\text{A}/\mu\text{s}$ ,  $V_{\text{DD}} \leq \text{BV}_{\text{DSS}}$ , starting  $T_J=25^\circ\text{C}$

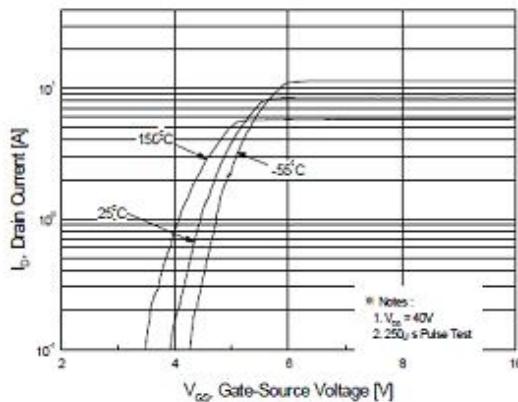
4. Pulse test : pulse width  $\leq 300\mu\text{s}$ , duty cycle  $\leq 2\%$

5. Essentially independent of operating temperature

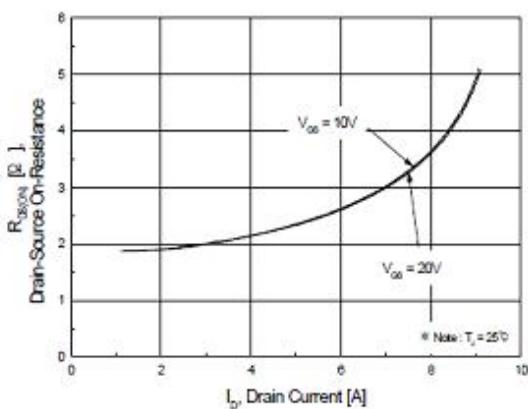
## 7. Test circuits and waveforms



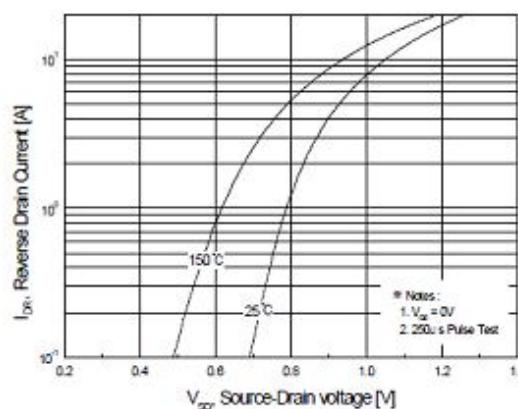
**Figure 1. On-Region Characteristics**



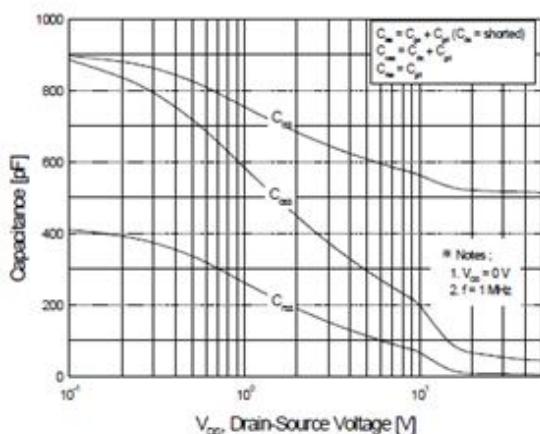
**Figure 2. Transfer Characteristics**



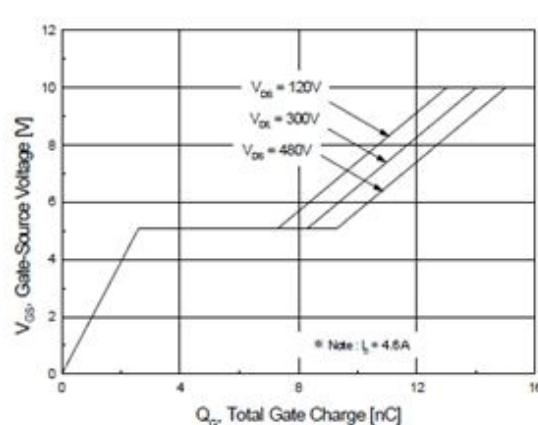
**Figure 3. On-Resistance Variation vs. Drain Current and Gate Voltage**



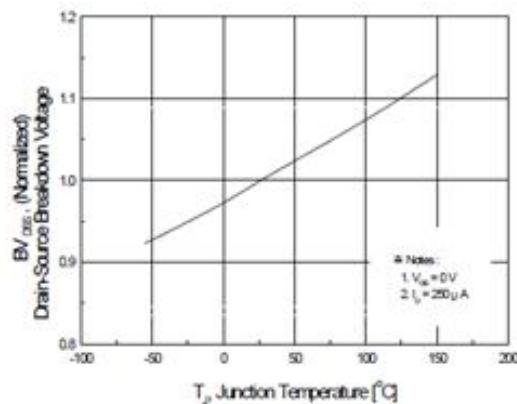
**Figure 4. Body Diode Forward Voltage Variation with Source Current and Temperature**



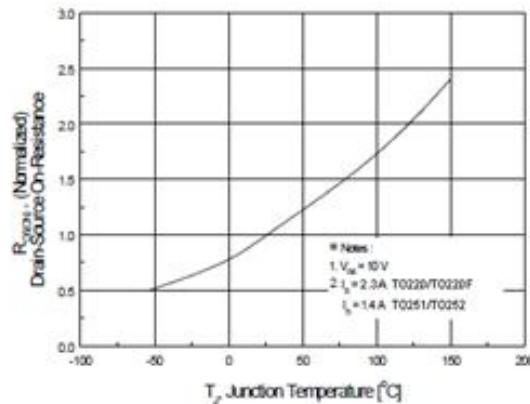
**Figure 5. Capacitance Characteristics**



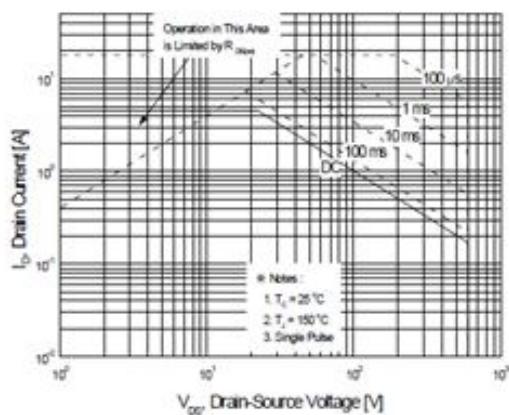
**Figure 6. Gate Charge Characteristics**



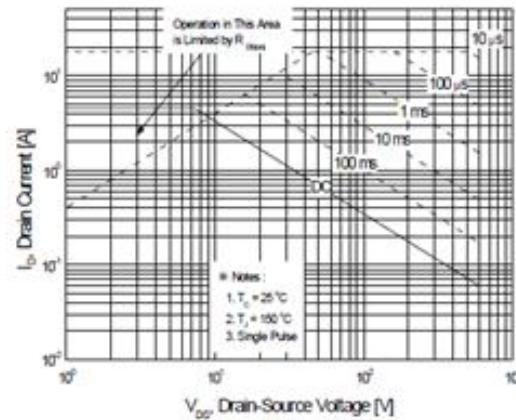
**Figure 7. Breakdown Voltage Variation vs Temperature**



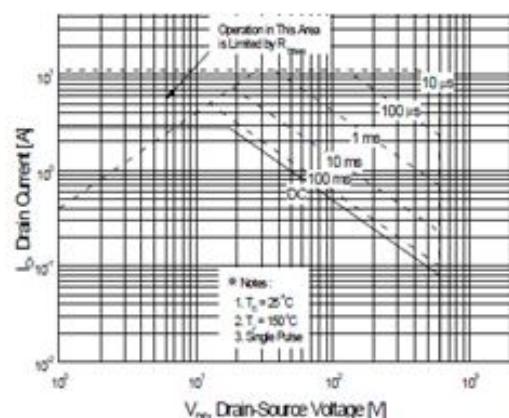
**Figure 8. On-Resistance Variation vs Temperature**



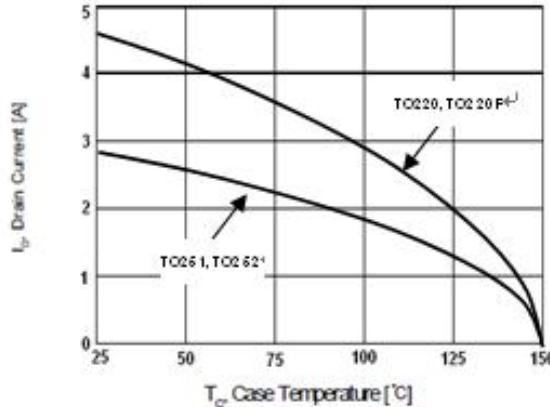
**Figure 9-1. Maximum Safe Operating Area for TO220**



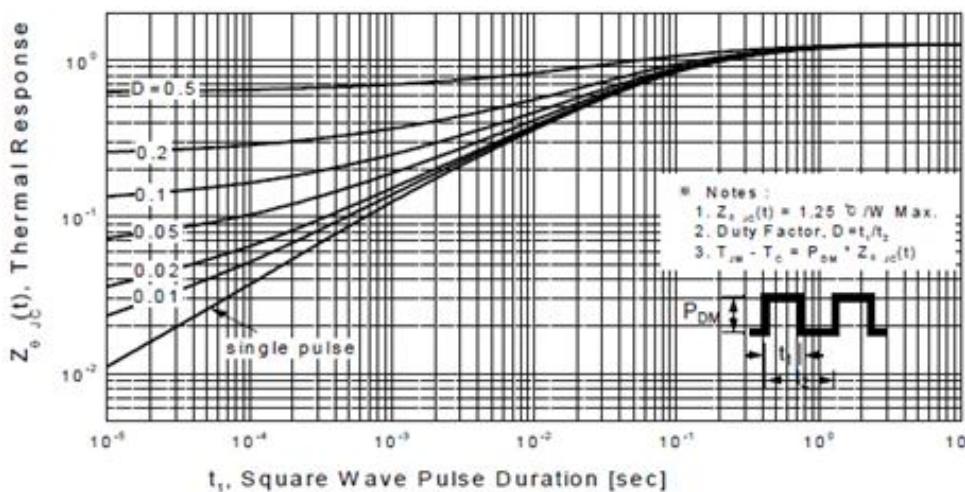
**Figure 9-2. Maximum Safe Operating Area for TO220F**



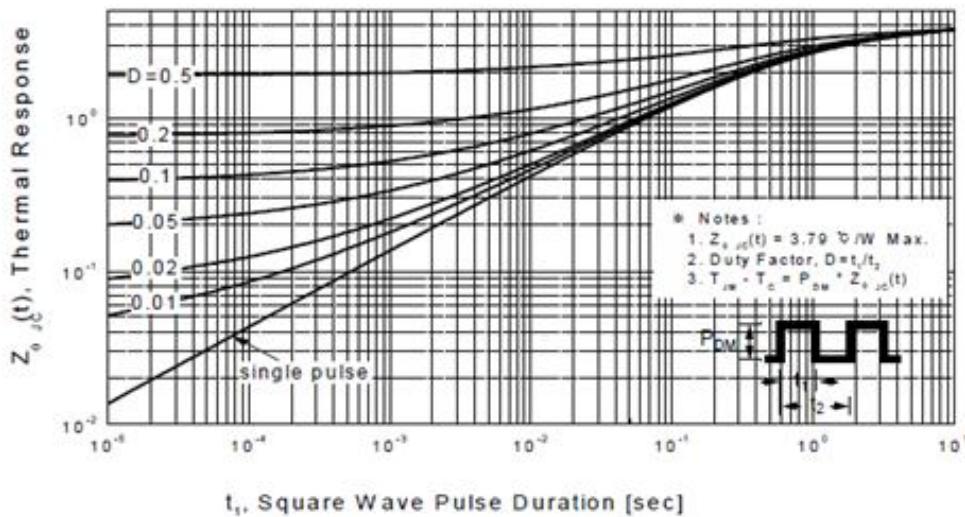
**Figure 9-3. Maximum Safe Operating Area for TO251, TO252**



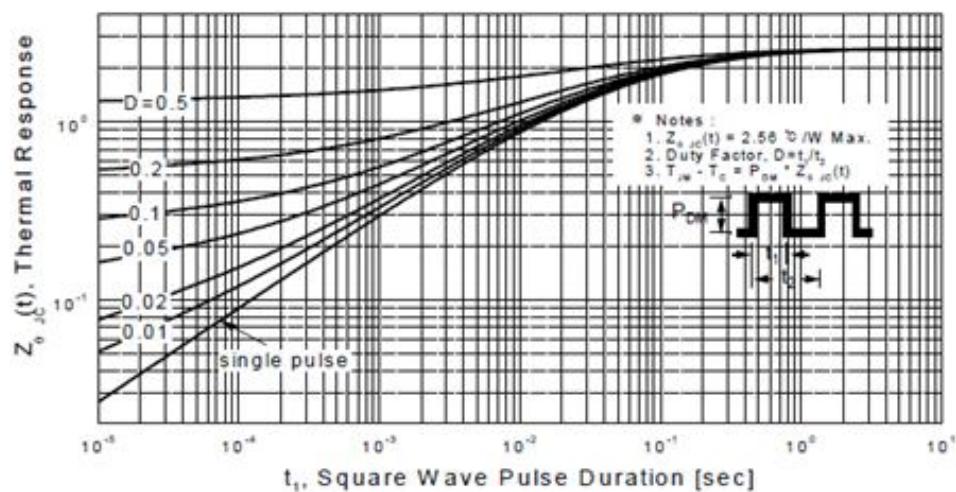
**Figure 10. Maximum Drain Current vs Case Temperature**



**Figure 11-1. Transient Thermal Response Curve T0220.**



**Figure 11-2. Transient Thermal Response Curve for T0220F.**



**Figure 11-3. Transient Thermal Response Curve for T0251/T0252.**